Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO. 263131US6PCT		SERIAL NO. 10/518,645	
(Modified)		PATENT AND TRAC	DEMARK OFFICE				
				APPLICANT			
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Hirofumi ONISHI, et al.			
				FILING DATE		GROUP	
				December 20, 2004			
				U.S. PATENT DOCUMENTS		<u> </u>	
EXAMINER	Γ	DOCUMENT	DATE	NAME CLASS SUB FILING DA			FILING DATE
INITIAL		NUMBER	DATE		CLASS	CLASS	IF APPROPRIATE
RML	AA	6 382 382	05/07/02	AVNY, Eli et al.			
RML	AB	2002/0117356	08/29/02	WITTKOPP, Scott Henry			
RML	AC	5 913 397	06/22/99	OKADA, Takashi et al.			
RML	AD	5 662 198	09/02/97	KOJIMA, Yolchi et al.			
	AE						
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	AM						
	AN						
			FO	REIGN PATENT DOCUMENTS		-	
		DOCUMENT DATE		2011177		TRANSLATION	
		NUMBER	DATE	COUNTRY		YES	
RML	AO	5-39866	02/19/93	JP (with English abstract)			NO
RMT.	AP	9-32919	02/07/97	JP (with English abstract)			NO
RML	AQ	11-182579	07/06/99	JP (with English abstract)			NO
RMT.	AR	2001-304355	10/31/01	JP (with English abstract)			NO
RML	AS	2-50550	04/09/90	JP			NO
	AT						
	AU						
	AV						
		OTHER RE	EFERENCES (Including Author, Title, Date, Pertinent	t Pages, e	tc.)	
	AW						
	AX						
							
	AY						
	AZ				InhA I	tional Refe	erences sheet(s) attached
Examiner /	/p; al	and M. Tomono	<u> </u>		Date Considered 05/28/2006		
Examiner /Richard M. Lorence/ Date Considered 05/28/2006 *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in							
"Examiner: Ir conformance	nitial if r	reterence is considered, ot considered. Include c	wnether or no opy of this fom	t citation is in conformance with MPEP 60 n with next communication to applicant.	J9; Uraw li	ne wrough	i citation if not in